



MAIL STOP RCE
PATENT
8053-1016

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Kazuhiro NAKAJIMA et al. Conf. 9942

Application No. 10/625,695 Group 2811

Filed July 24, 2003 Examiner Ori Nadav

PRODUCTION PROCESS FOR PRODUCING
SEMICONDUCTOR DEVICES, SEMICONDUCTOR
DEVICES PRODUCED THEREBY, AND TEST
SYSTEM FOR CARRYING OUT YIELD-RATE
TEST IN PRODUCTION OF SUCH
SEMICONDUCTOR DEVICES

AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

September 9, 2005

Sir:

In response to the Official Action mailed May 10, 2005,
please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this
paper.

Amendments to the Claims are reflected in the listing
of claims which begins on page 3 of this paper.

Amendments to the Drawings begin on page 10 of this
paper.

Remarks begin on page 11 of this paper.

An **Appendix** follows the signature page of this paper.